



# FDB28N30

## N-Channel UniFET™ MOSFET

300 V, 28 A, 129 mΩ

### Features

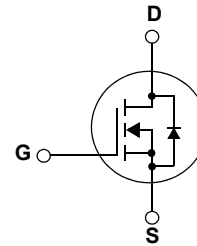
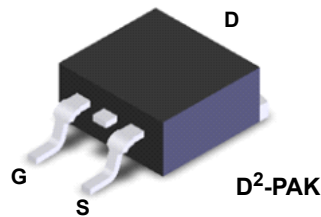
- $R_{DS(on)} = 108 \text{ m}\Omega$  (Typ.) @  $V_{GS} = 10 \text{ V}$ ,  $I_D = 14 \text{ A}$
- Low Gate Charge (Typ. 39 nC)
- Low  $C_{rss}$  (Typ. 35 pF)
- 100% Avalanche Tested
- RoHS Compliant

### Applications

- Uninterruptible Power Supply
- AC-DC Power Supply

### Description

UniFET™ MOSFET is Fairchild Semiconductor®'s high voltage MOSFET family based on planar stripe and DMOS technology. This MOSFET is tailored to reduce on-state resistance, and to provide better switching performance and higher avalanche energy strength. This device family is suitable for switching power converter applications such as power factor correction (PFC), flat panel display (FPD) TV power, ATX and electronic lamp ballasts.



### MOSFET Maximum Ratings $T_C = 25^\circ\text{C}$ unless otherwise noted\*

Symbol	Parameter	FDB28N30	Unit
$V_{DSS}$	Drain to Source Voltage	300	V
$V_{GSS}$	Gate to Source Voltage	$\pm 30$	V
$I_D$	Drain Current	- Continuous ( $T_C = 25^\circ\text{C}$ )	28
		- Continuous ( $T_C = 100^\circ\text{C}$ )	19
$I_{DM}$	Drain Current	- Pulsed (Note 1)	112
$E_{AS}$	Single Pulsed Avalanche Energy	(Note 2)	588
$I_{AR}$	Avalanche Current	(Note 1)	28
$E_{AR}$	Repetitive Avalanche Energy	(Note 1)	25
$dv/dt$	Peak Diode Recovery $dv/dt$	(Note 3)	4.5
$P_D$	Power Dissipation	( $T_C = 25^\circ\text{C}$ )	250
		- Derate above $25^\circ\text{C}$	2.0
$T_J, T_{STG}$	Operating and Storage Temperature Range	-55 to +150	$^\circ\text{C}$
$T_L$	Maximum Lead Temperature for Soldering Purpose, 1/8" from Case for 5 Seconds	300	$^\circ\text{C}$

### Thermal Characteristics

Symbol	Parameter	FDB28N30	Unit
$R_{\theta JC}$	Thermal Resistance, Junction to Case, Max.	0.5	$^\circ\text{C}/\text{W}$
$R_{\theta JA}^*$	Thermal Resistance, Junction to Ambient*	40	
$R_{\theta JA}$	Thermal Resistance, Junction to Ambient, Max.	62.5	

\*When mounted on the minimum pad size recommended (PCB Mount)

**Package Marking and Ordering Information**  $T_C = 25^\circ\text{C}$  unless otherwise noted

Device Marking	Device	Package	Reel Size	Tape Width	Quantity
FDB28N30	FDB28N30TM	D2-PAK	330mm	24mm	800

**Electrical Characteristics**

Symbol	Parameter	Test Conditions	Min.	Typ.	Max.	Unit
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**Off Characteristics**

$BV_{DSS}$	Drain to Source Breakdown Voltage	$I_D = 250\mu\text{A}, V_{GS} = 0\text{V}, T_J = 25^\circ\text{C}$	300	-	-	V
$\Delta BV_{DSS} / \Delta T_J$	Breakdown Voltage Temperature Coefficient	$I_D = 250\mu\text{A}$ , Referenced to $25^\circ\text{C}$	-	0.4	-	$V/^\circ\text{C}$
$I_{DSS}$	Zero Gate Voltage Drain Current	$V_{DS} = 300\text{V}, V_{GS} = 0\text{V}$ $V_{DS} = 240\text{V}, T_C = 125^\circ\text{C}$	-	-	1 10	$\mu\text{A}$
$I_{GSS}$	Gate to Body Leakage Current	$V_{GS} = \pm 30\text{V}, V_{DS} = 0\text{V}$	-	-	$\pm 100$	nA

**On Characteristics**

$V_{GS(th)}$	Gate Threshold Voltage	$V_{GS} = V_{DS}, I_D = 250\mu\text{A}$	3.0	-	5.0	V
$R_{DS(on)}$	Static Drain to Source On Resistance	$V_{GS} = 10\text{V}, I_D = 14\text{A}$	-	0.108	0.129	$\Omega$
$g_{FS}$	Forward Transconductance	$V_{DS} = 40\text{V}, I_D = 14\text{A}$	-	24.8	-	S

**Dynamic Characteristics**

$C_{iss}$	Input Capacitance	$V_{DS} = 25\text{V}, V_{GS} = 0\text{V}$ $f = 1\text{MHz}$	-	1690	2250	pF
$C_{oss}$	Output Capacitance		-	305	405	pF
$C_{rss}$	Reverse Transfer Capacitance		-	35	50	pF
$Q_g$	Total Gate Charge at 10V	$V_{DS} = 240\text{V}, I_D = 28\text{A}$ $V_{GS} = 10\text{V}$	-	39	50	nC
$Q_{gs}$	Gate to Source Gate Charge		-	12	-	nC
$Q_{gd}$	Gate to Drain "Miller" Charge		(Note 4)	-	17	-

**Switching Characteristics**

$t_{d(on)}$	Turn-On Delay Time	$V_{DD} = 150\text{V}, I_D = 28\text{A}$ $R_G = 25\Omega$	-	35	80	ns
$t_r$	Turn-On Rise Time		-	135	280	ns
$t_{d(off)}$	Turn-Off Delay Time		-	79	168	ns
$t_f$	Turn-Off Fall Time		(Note 4)	-	69	148

**Drain-Source Diode Characteristics**

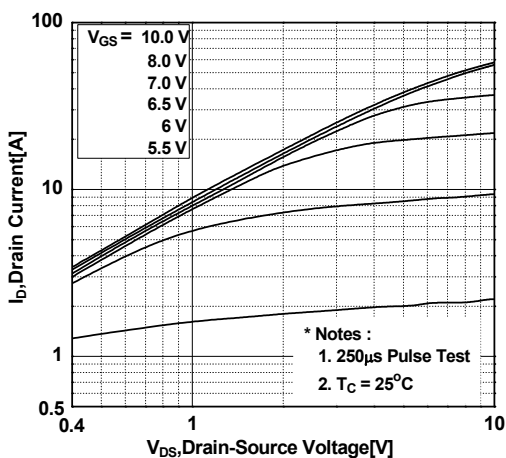
$I_S$	Maximum Continuous Drain to Source Diode Forward Current	-	-	28	A	
$I_{SM}$	Maximum Pulsed Drain to Source Diode Forward Current	-	-	112	A	
$V_{SD}$	Drain to Source Diode Forward Voltage	$V_{GS} = 0\text{V}, I_{SD} = 28\text{A}$	-	-	1.4	V
$t_{rr}$	Reverse Recovery Time	$V_{GS} = 0\text{V}, I_{SD} = 28\text{A}$	-	279	-	ns
$Q_{rr}$	Reverse Recovery Charge	$dI_F/dt = 100\text{A}/\mu\text{s}$	-	2.7	-	$\mu\text{C}$

Notes:

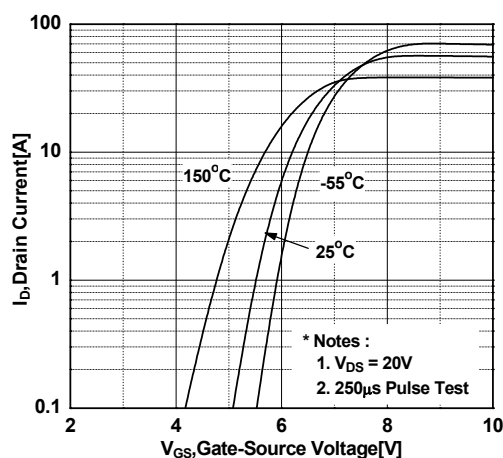
1. Repetitive Rating: Pulse width limited by maximum junction temperature
2.  $L = 1.5\text{mH}, I_{AS} = 28\text{A}, V_{DD} = 50\text{V}, R_G = 25\Omega$ , Starting  $T_J = 25^\circ\text{C}$
3.  $I_{SD} \leq 28\text{A}, di/dt \leq 200\text{A}/\mu\text{s}, V_{DD} \leq BV_{DSS}$ , Starting  $T_J = 25^\circ\text{C}$
4. Essentially Independent of Operating Temperature Typical Characteristics

## Typical Performance Characteristics

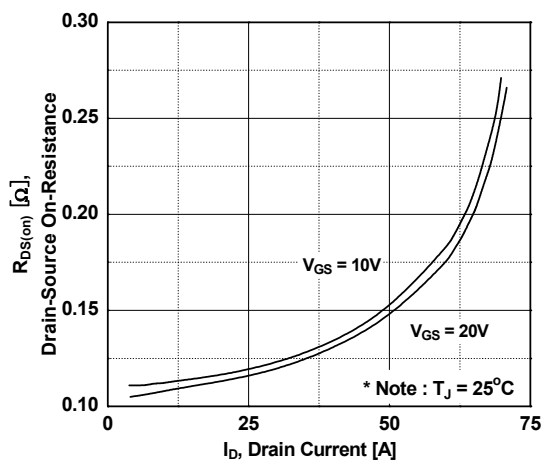
**Figure 1. On-Region Characteristics**



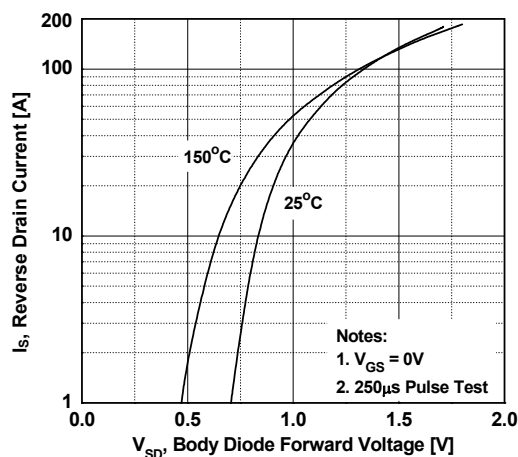
**Figure 2. Transfer Characteristics**



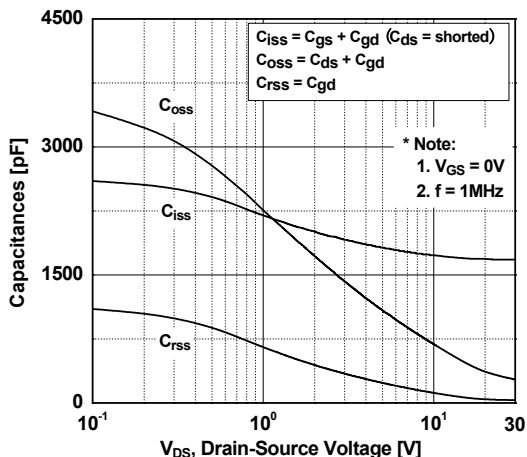
**Figure 3. On-Resistance Variation vs. Drain Current and Gate Voltage**



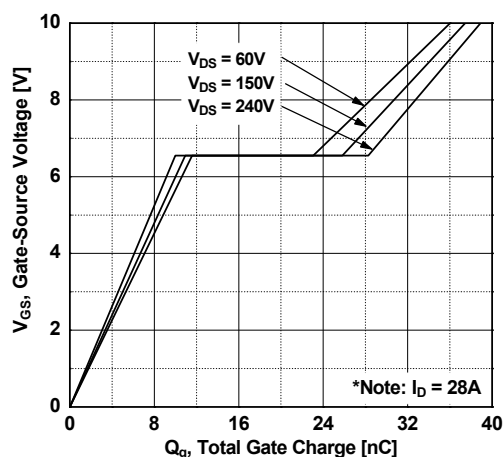
**Figure 4. Body Diode Forward Voltage Variation vs. Source Current and Temperature**



**Figure 5. Capacitance Characteristics**



**Figure 6. Gate Charge Characteristics**



Typical Performance Characteristics (Continued)

Figure 7. Breakdown Voltage Variation vs. Temperature

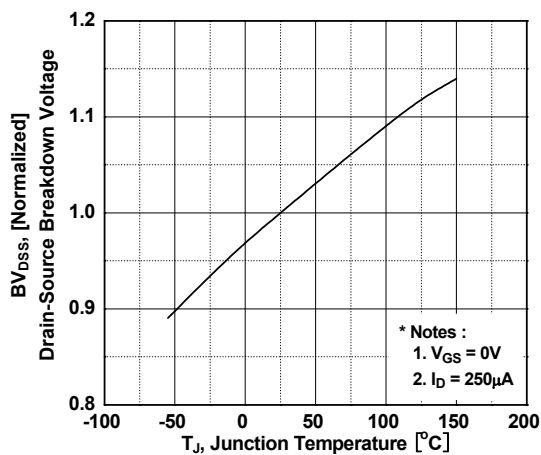


Figure 8. On-Resistance Variation vs. Temperature

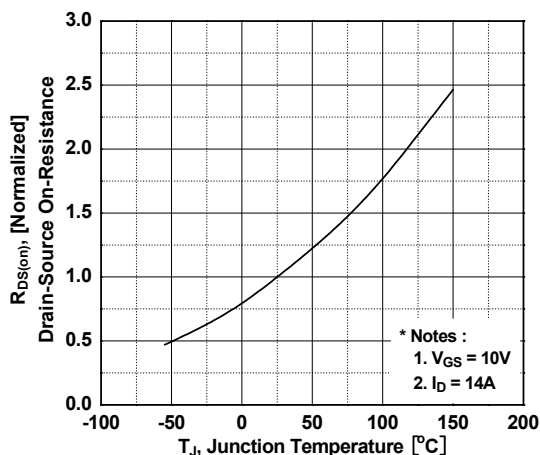


Figure 9. Maximum Safe Operating Area

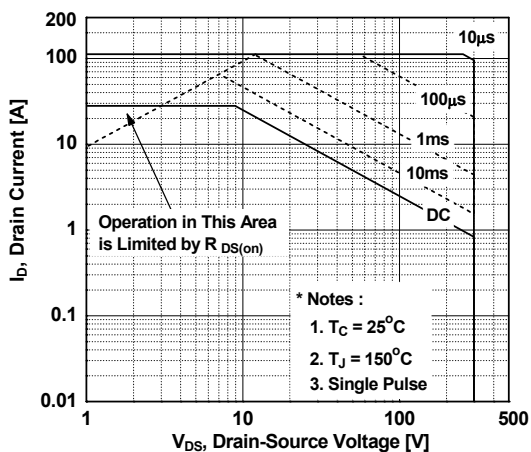


Figure 10. Maximum Drain Current vs. Case Temperature

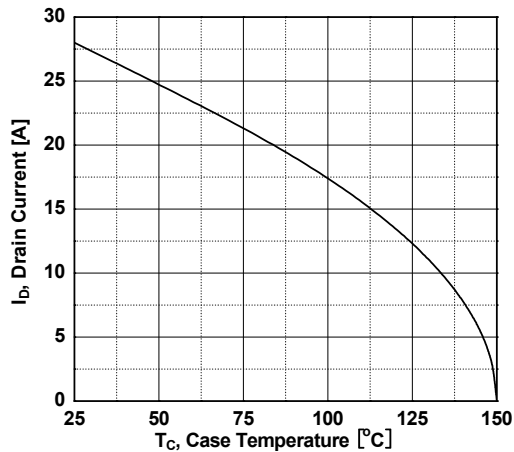
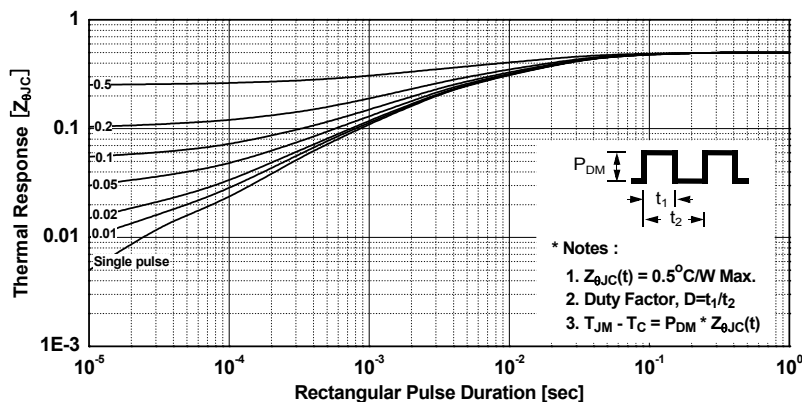
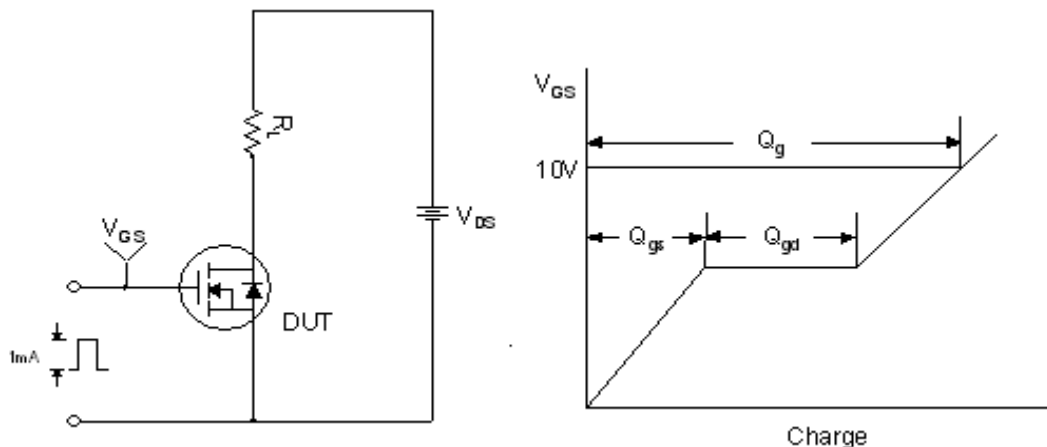


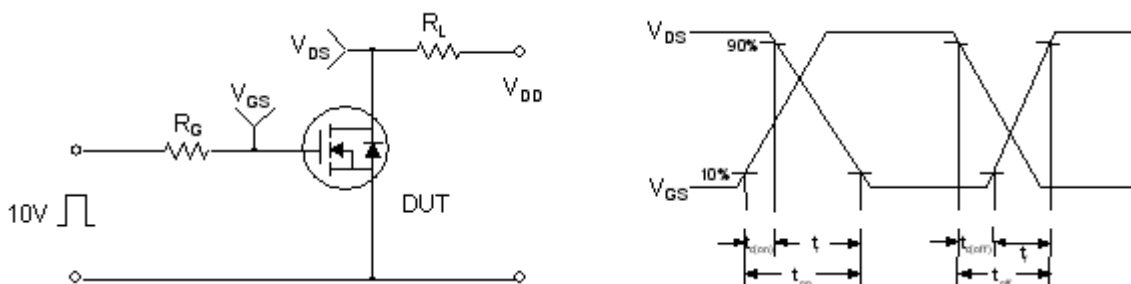
Figure 11. Transient Thermal Response Curve



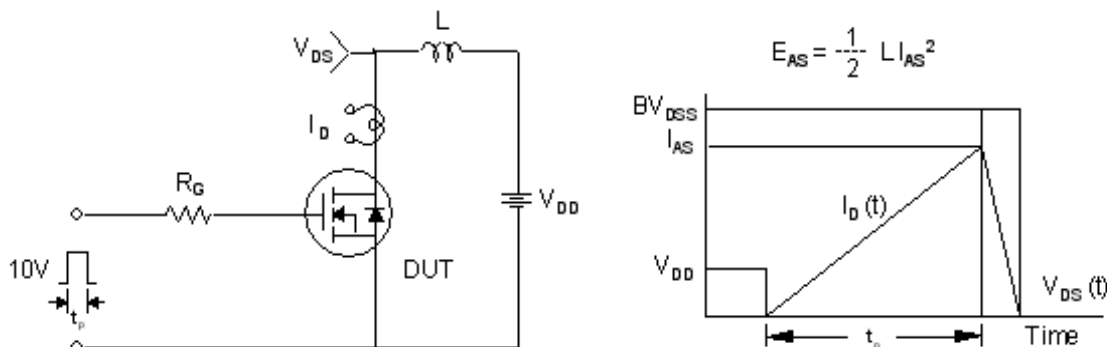
**Gate Charge Test Circuit & Waveform**



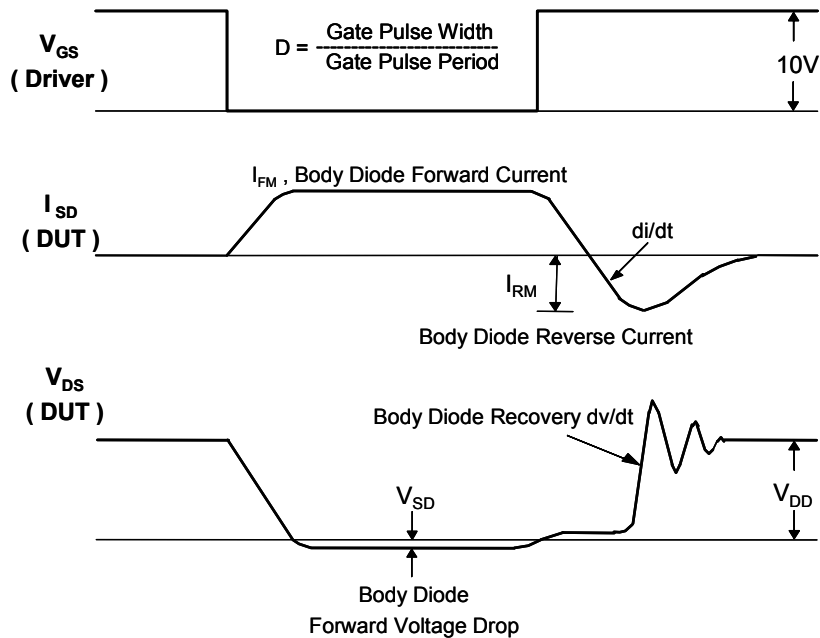
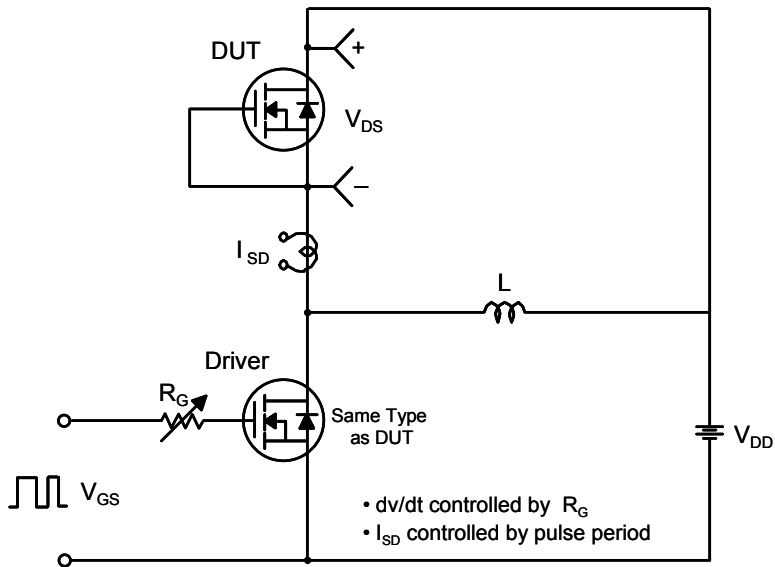
**Resistive Switching Test Circuit & Waveforms**



**Unclamped Inductive Switching Test Circuit & Waveforms**

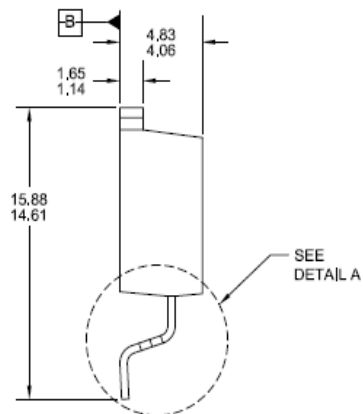
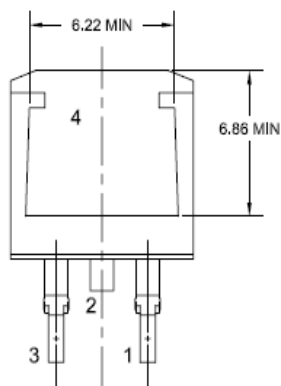
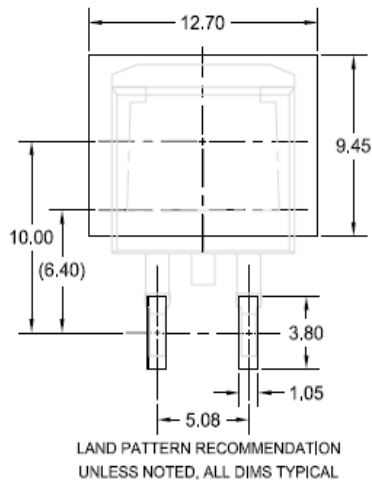
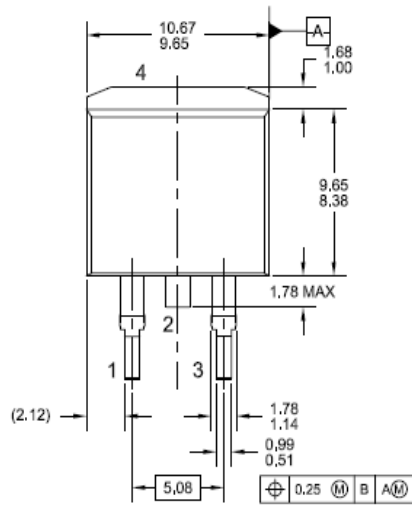


Peak Diode Recovery dv/dt Test Circuit & Waveforms

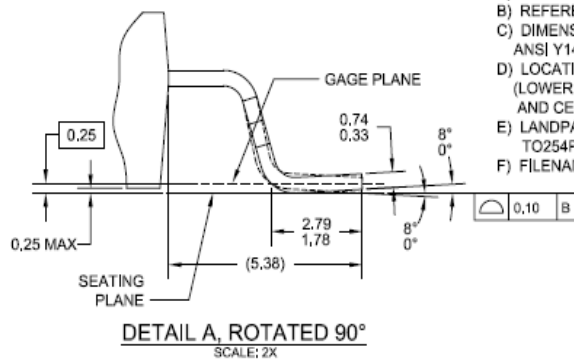


## Mechanical Dimensions

# D<sup>2</sup>PAK



- NOTES: UNLESS OTHERWISE SPECIFIED  
 A) ALL DIMENSIONS ARE IN MILLIMETERS.  
 B) REFERENCE JEDEC, TO-263, VARIATION AB.  
 C) DIMENSIONING AND TOLERANCING PER ANSI Y14.5M - 1994.  
 D) LOCATION OF THE PIN HOLE MAY VARY (LOWER LEFT CORNER, LOWER CENTER AND CENTER OF THE PACKAGE).  
 E) LANDPATTERN RECOMMENDATION PER IPC TO254P1524X482-3N  
 F) FILENAME: TO263A02REV6


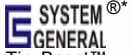





Dimensions in Millimeters



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| AccuPower™  | F-PFET™   | PowerTrench®  |  |
| AX-CAP®*  | FRFET®  | PowerXS™  | TinyBoost™  |
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Datasheet Identification	Product Status	Definition
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Preliminary	First Production	Datasheet contains preliminary data; supplementary data will be published at a later date. Fairchild Semiconductor reserves the right to make changes at any time without notice to improve design.
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